

**Notice of References Cited**

Application/Control No.

10/577,473

Applicant(s)/Patent Under  
Reexamination  
YAMANAKA ET AL.

Examiner

RICKY NGON

Art Unit

4148

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0162557	12-2002	Shida, Daiki	455/521
*	B	US-2003/0119559	11-2002	Chitrapu, Prabhakar R.	455/562
*	C	US-2001/0050366	12-2001	Okuyama, Kuniyuki	257/72
*	D	US-6,445,151	09-2002	Nakano et al.	318/434
*	E	US-2002/0115478	08-2002	Fujisawa et al.	455/567
*	F	US-2002/0143469	10-2002	Alexander et al.	702/2
*	G	US-6,513,129	06-1999	Tentij et al.	714/4
*	H	US-6,195,549	02-2001	Nakajima, Keiichi	455/424
*	I	US-5,694,129	12-1997	Fujinawa et al.	342/22
*	J	US-2004/0075552	10-2002	Rao et al.	340/539.1
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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